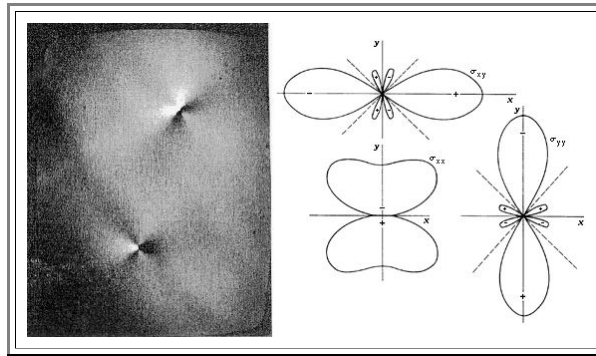


Infrared Microscopy of Defects

- The strain field of dislocations shifts the polarization plane of light. A specimen (with two polished surfaces) between almost crossed polarizers thus transmits more or less light than the bulk around defects



- The picture shows two edge dislocations in **GaAs** parallel to the optical axis. The contrast is directly proportional to the sign and magnitude of the [strain field](#) (or stress-field, which is shown for comparison)

Illustration